

Supporting Information



Figure S1. One photograph of large-scale reduced graphene oxide materials (9.7465 g, about 500 mL).

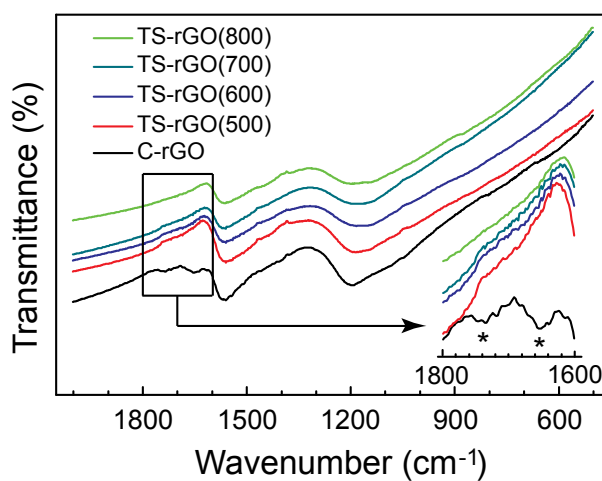


Figure S2. FT-IR spectra of C-rGO and TS-rGO prepared at various temperature from 500°C to 800°C.

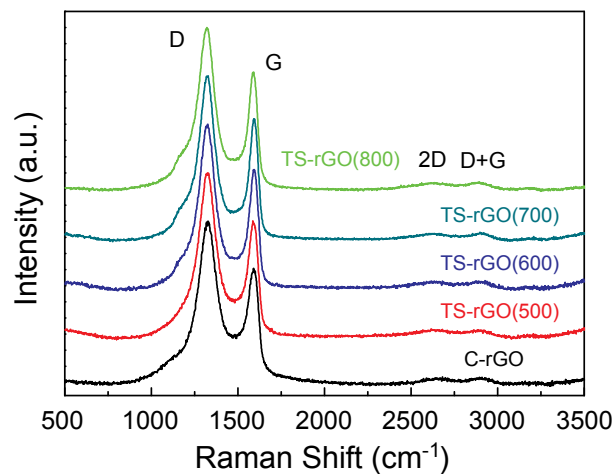


Figure S3. Raman spectra of C-rGO and TS-rGO prepared at various temperature from 500°C to 800°C.

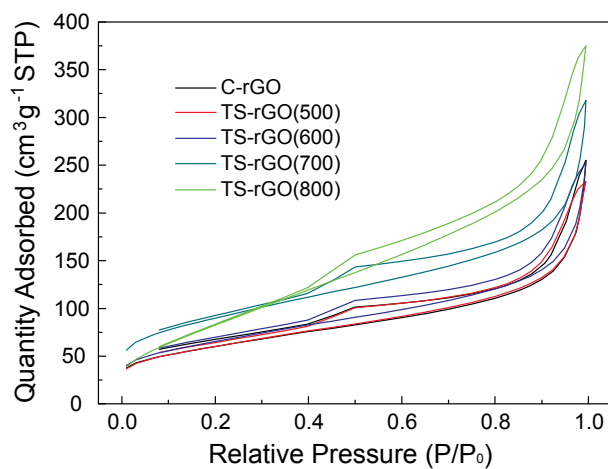


Figure S4. N₂ adsorption/desorption isotherms of C-rGO and TS-rGO materials prepared at various temperature from 500°C to 800°C.

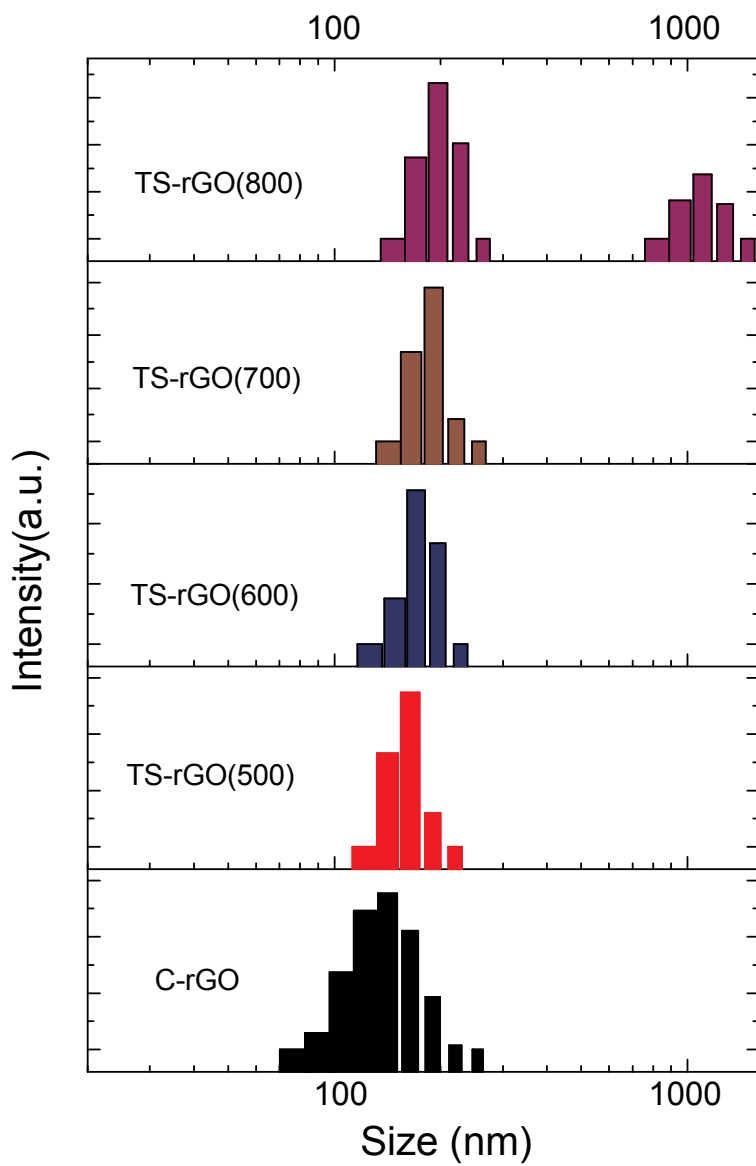


Figure S5. Particle size distribution of C-rGO and TS-rGO materials prepared at various temperature from 500°C to 800°C.

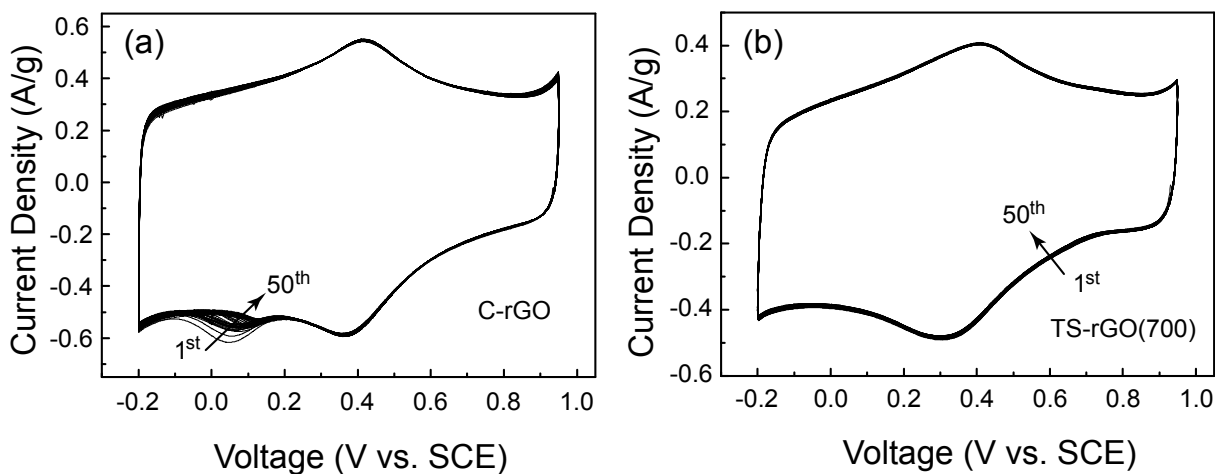


Figure S6. Comparison of CV curves for C-rGO and TS-rGO(700) at a scan rate of 2 mV/s.

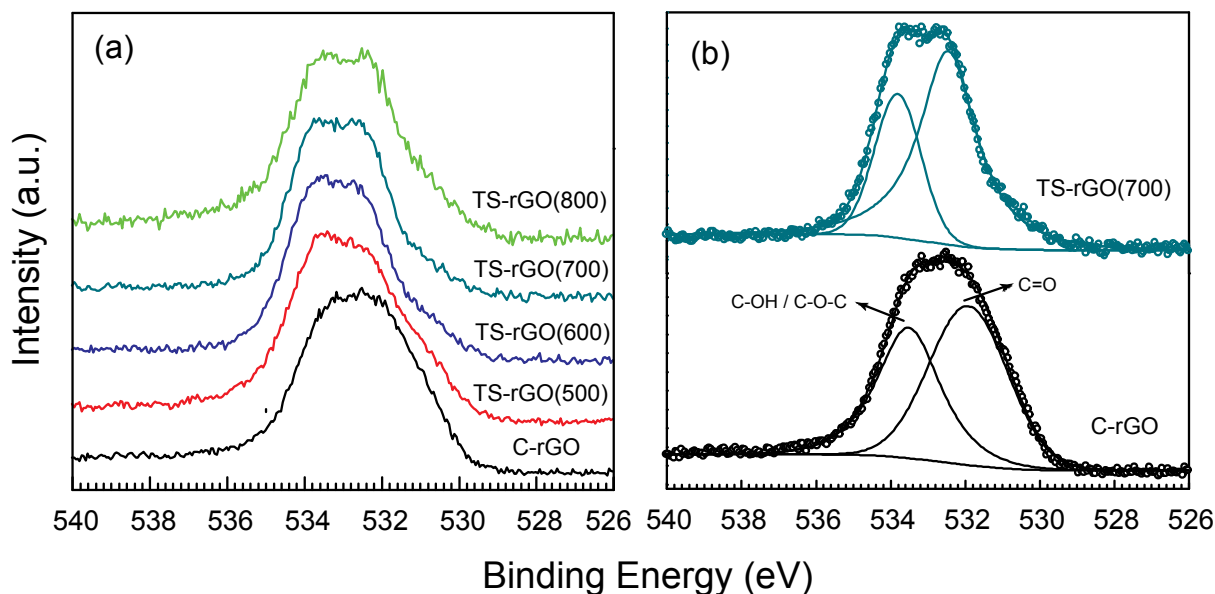


Figure S7. (a) Comparisons of O1s XPS profiles of C-rGO and TS-rGO materials prepared at various temperature from 500°C to 800°C. (b) The experimental and fitted O1s XPS profiles of C-rGO and TS-rGO(700).

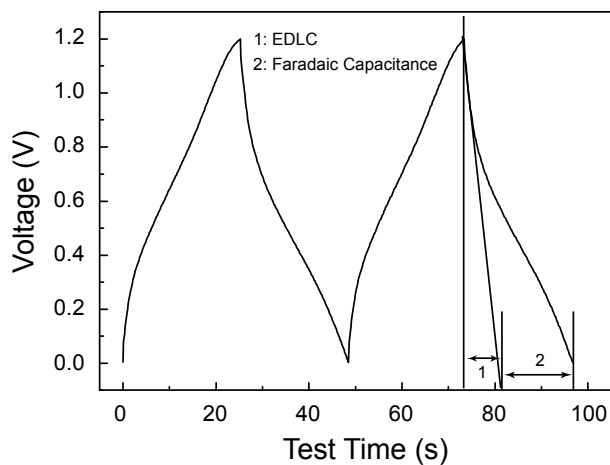


Figure S8. Galvanostatic charge/discharge curves of TS-rGO(700) material at a current density of 4A/g in 1 mol/L H₂SO₄ aqueous solution containing 0.1 mol/L VO²⁺/VO₃⁻ ions.

Table S1 Intensity ratios of D-band to G-band in Raman spectra of C-rGO and TS-rGO materials.

Samples	C-rGO	TS-rGO(500)	TS-rGO(600)	TS-rGO(700)	TS-rGO(800)
I _D /I _G	1.41	1.42	1.39	1.36	1.38